

EE 105, Fall 1998 Midterm #1 Professor CJ Spanos

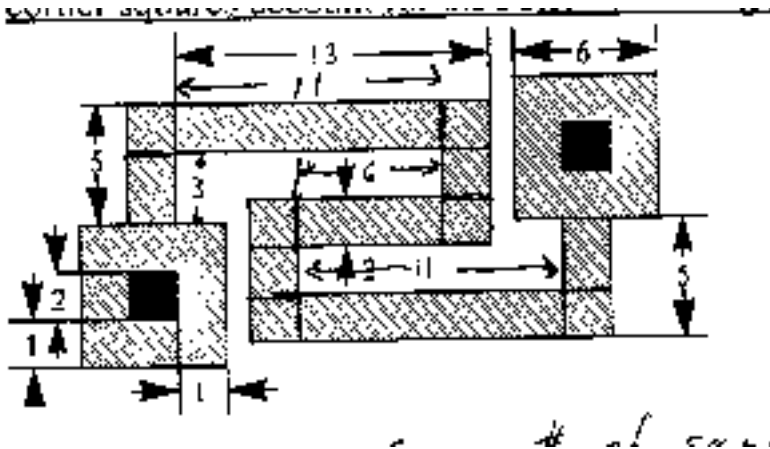
Problem #1 (35 points)

What is the mass-action law (as it applies to holes and electrons in Silicon, of course)? (5 pts)

What is the concentration of holes, electrons and ions if Si is doped with 10^{16} As atoms/cm³ at room temperature? ($n_i=10^{10}$) (5 pts)

What are the four types of currents you can find across a p-n junction at equilibrium? (6 pts)

Find the resistance of the following structure (drawn to scale), if the R_s is 10 Ohms/square. Assume corner squares account for 0.56 R_s , while "dogbone" contact areas amount to 0.65 squares. (8 pts)



At what gate-to-bulk bias potential do you obtain the *minimum* possible capacitance of an MOS structure on top of a p-type substrate? (5 pts)

Consider an MOS structure on top of a *n-type* substrate, while using *n+* type gate. Mark the type of charges (ie. positive ions / negative ions / free electrons / free holes) on the gate and the substrate as a function of the biasing conditions on the following table (6 pts):

Bias	Gate Charges	Substrate Charges
Accumulation		
Depletion		

Inversion		
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Problem #2 (40 points)

Sometimes, a special "V_t-adjust" implant is being used in order to set the threshold voltage of a device at a specific value. The process sequence described next is an example of this. Please follow the steps and draw the two cross sections at the steps indicated (10 pts)

Step 0: start with 10^{15} atoms/cm³ p-type wafer and 0.5 μ m of isolation oxide.

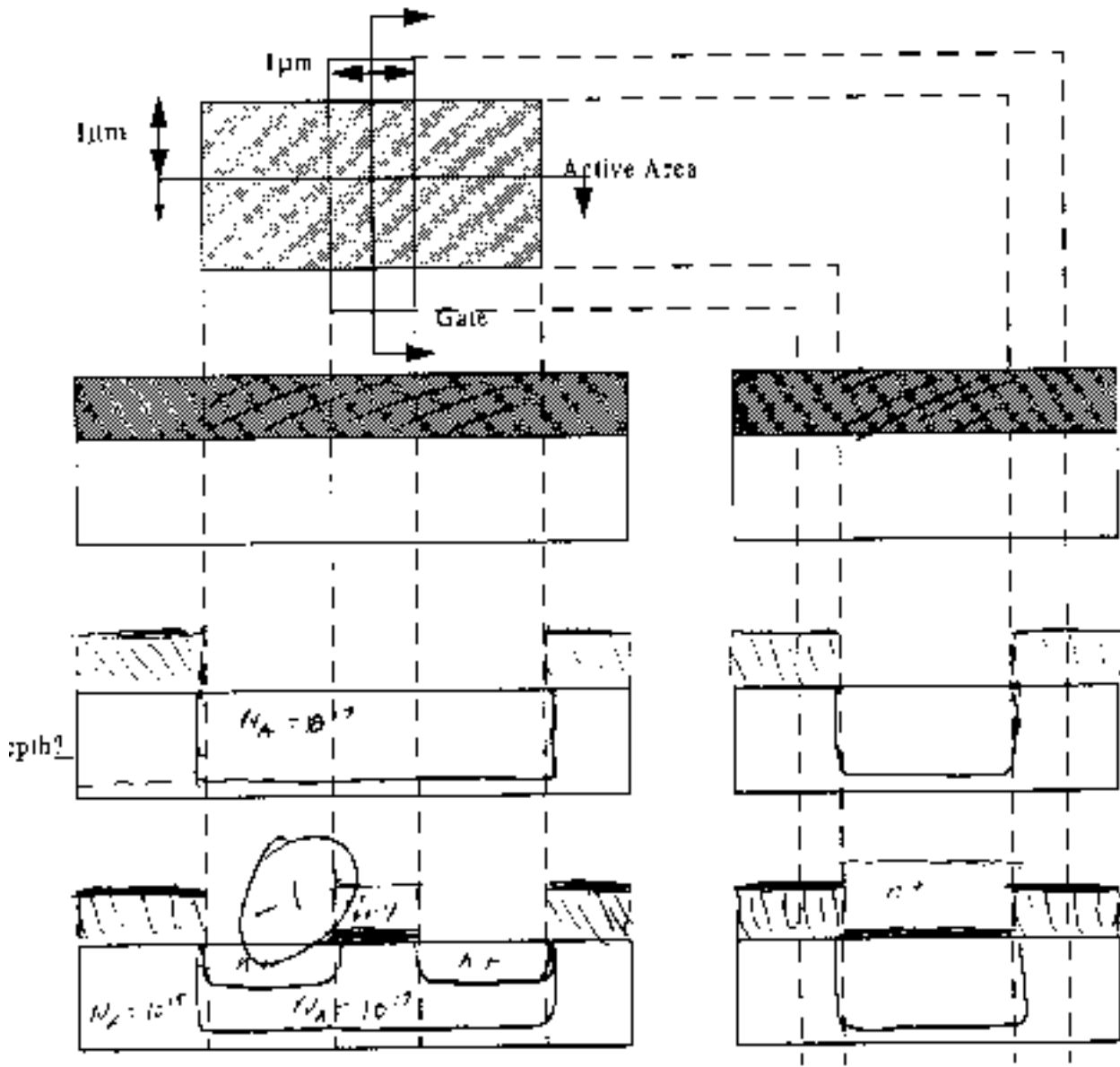
Step 1: use mask shown to create active area (ie. remove the thick gate oxide in shaded region.)

Step 2: implant a dose of 10^{12} atoms of Boron per cm², so that the annealed profile has a uniform concentration of 10^{17} /cm³ from the surface down to a finite depth. (draw the two cross sections marked on the graph and calculate and mark the depth of the annealed Boron profile.)

Step 3: grow 100 Angstroms of gate oxide

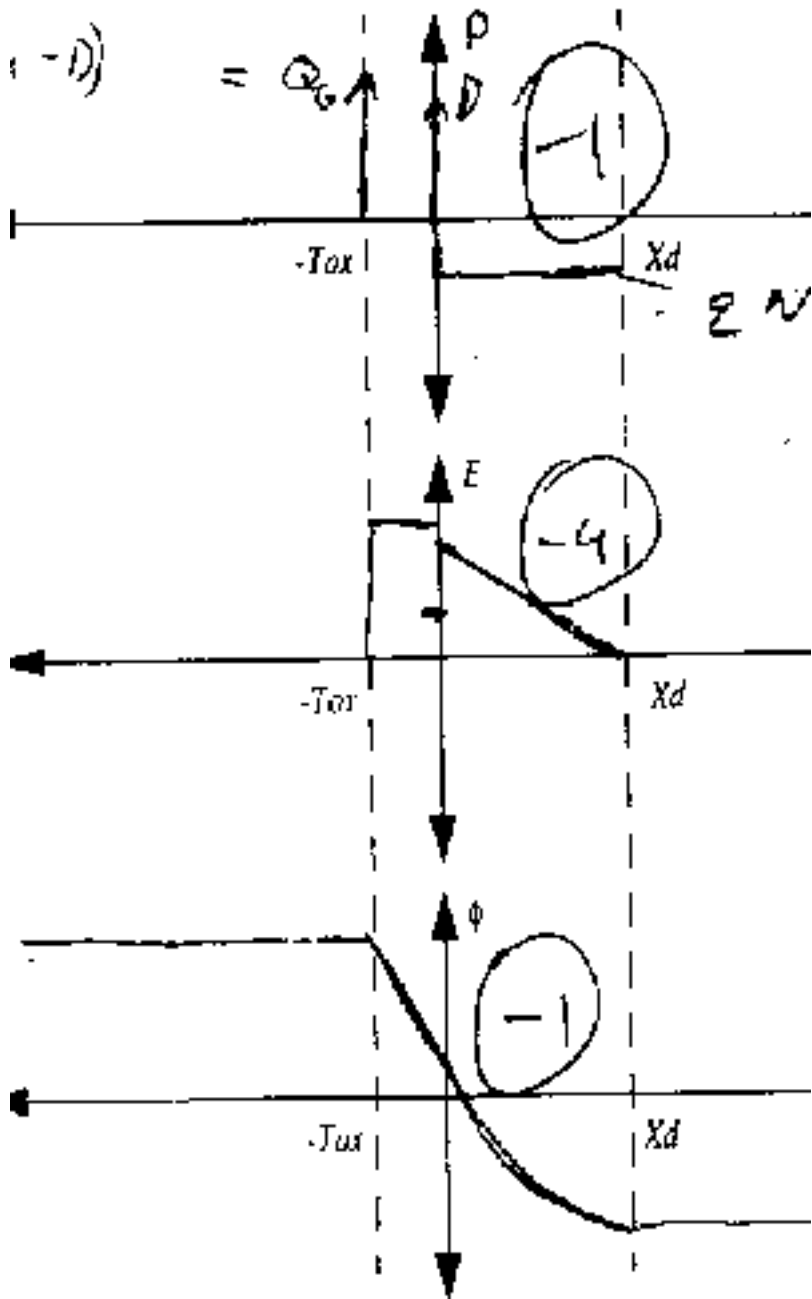
Step 4: deposit and pattern gate

Step 5: Implant n+ source/drain and gate, to a depth of 0.5 μ m. (draw the two cross sections marked on the graph)



On a different example of using the V_t adjust implant, make the assumption that the implant is very shallow, so all its charge can be approximated by a delta function at the surface of the channel. Now consider the specific case where we have n^+ poly (assume $\phi_m = 0.55\text{V}$), p -type substrate with $10^{16}/\text{cm}^3$ concentration of Boron, and a T_{ox} of 100 Angstroms. The unknown in this problem is the dose D and the polarity of the implanted material, in # of atoms/ cm^2 .

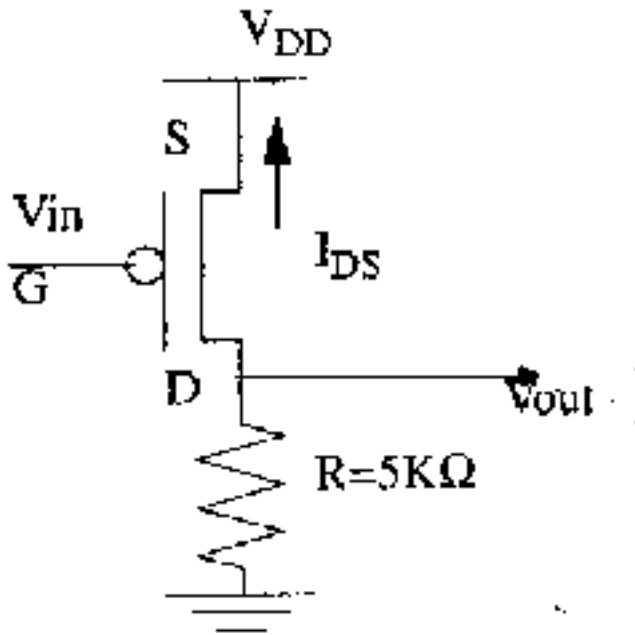
Sketch the charge density (ρ), electric field (E) and potential (ϕ) diagrams and label all values with the proper symbolic expressions. (15 pts)



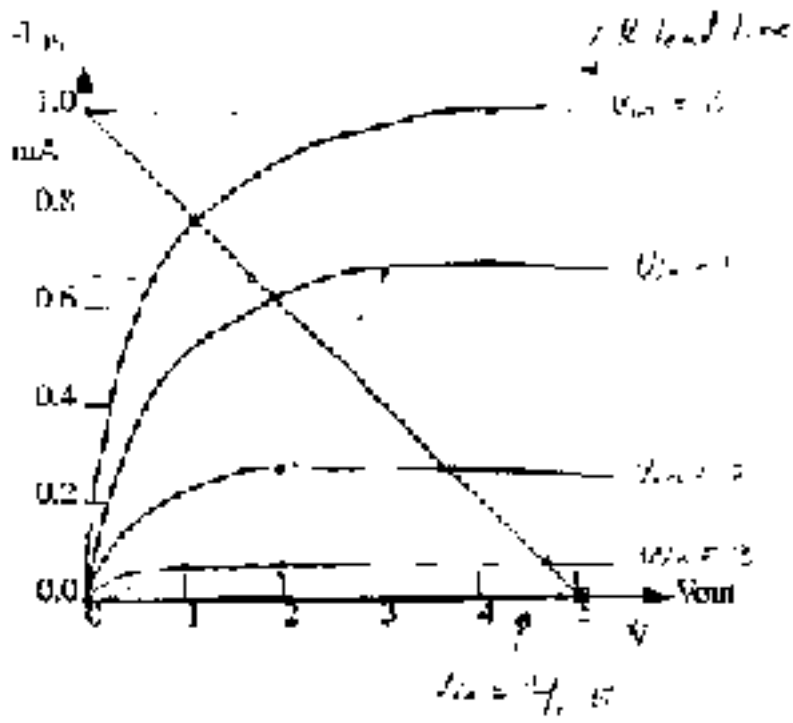
Find the dose and type (donor or acceptor) of the channel implant so that the depletion depth X_d is exactly $0.1\mu\text{m}$ when $V_{GS}=V_{BS}=0\text{V}$ ($\epsilon_0=8.85 \times 10^{-14}\text{F/cm}$, $\epsilon_{ox}=3.9\epsilon_0$, $\epsilon_{Si}=11.7\epsilon_0$, electron charge is $-1.6 \times 10^{-19}\text{Cb}$) (15 pts)

Problem #3 (25 points)

You just found in your basement a batch of old, n-type wafers from the 70s. You decide to make some cheap inverters on them, just by using p-channel transistors and diffusion resistors. This is the design of the inverter you come up with:



Now, assume that W/L is $10/2$, $V_{DD}=5V$, $V_{tp}=-1V$, $\mu_p C_{ox}$ is $25\mu A/V^2$ and $\lambda_p=0V^{-1}$. Sketch the load line diagrams for the resistor and the transistor, and mark the approximate values of V_{out} for V_{in} taking the values $0V$, $1V$, $2V$, $3V$, $4V$ and $5V$. Make sure to indicate the status of the transistor at each point. (15 pts)



Last question! Draw the small signal equivalent circuit and calculate A_v when $V_{in}=2V$. (10 pts)

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